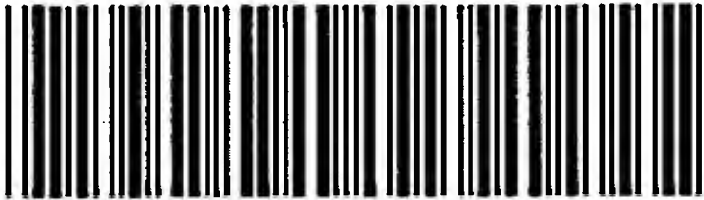


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/069,161	MARCHANT, NILS RAMON	
	Examiner	Art Unit	
	Binh Q. Nguyen	2664	

SEARCHED			
Class	Subclass	Date	Examiner
370	216	12/6/2005	BQN
370	323	12/6/2005	BQN
370	462	12/6/2005	BQN
364	474.15	12/6/2005	BQN
370	236.1	12/6/2005	BQN
370	229	12/6/2005	BQN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	12/6/2005	BQN
Consulted with Wellington Chin	12/5/2005	BQN